## Notice of References Cited Application/Control No. O9/769,293 Examiner O9/769 Applicant(s)/Patent Under Reexamination HINO ET AL. Examiner O9/769,293 Examiner O9/769,293 Examiner O9/769,293 Art Unit O9/769,293 Page 1 of 1

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## **NON-PATENT DOCUMENTS**

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